## **SPECIFICATION FOR UV-VIS SPECTROPHOTOMETER**

Analysis of solids and liquid sample

MILLER

1050 lines / mm or more and Beam splitter

Sources Pre-aligned deuterium and tungsten and tungsten

halogen lamps with automatic source change.

Detector Solid state detector/ PMT

Wavelength range 190 - 1100 nm

**Stray radiation** minimum 0.02 % T at 220, 340, 370 nm

Wavelength accuracy +/- 0.1nm

Wavelength repeatability : must be minimum  $\pm$  0.1 nm

Bandpass (Variable) : 0.5, 1, 2, 5, 20 nm (Variable bandwidth)

Baseline flatness with Slit of 0.5 nm must be ±0.00005 A

Photometric repeatability +/-0.001 A at 1 A

Photometric accuracy  $\pm 0.005$  Abs

Photometric stability  $\pm 0.0002$  Abs/ hr

Photometric noise less than  $\pm 0.00005$ 

Baseline flatness  $\pm 0.001 \text{ A}$ 

Resolution should be minimum 0.5 nm

Stability must be minimum **0.00015** A/h

Software Windows based operating Software. with Computer, laser Printer & 2 KVA UPS

## Accessories:

• Quartz cuvette 10mm path length- 1 pair. Cuvette

• Thin film sample holder for the analysis of thin films.

• Integrating Sphere attachment for the analysis of powder samples Warranty: 3 years warranty for the complete instrument

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Production C

Do Renjamaden B.